

Supplementary Information

Ultralow detection limit and high sensitivity X-ray detector of high-quality MAPbBr₃ perovskite single crystals

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Equation S1

The dark current drift, which is used to evaluate the degree of dark current drift, is expressed as:

$$Drift = \frac{J_t - J_0}{t \cdot E}$$

where J_t and J_0 are the current densities at the beginning and end points, respectively; E is the electric field; and t is the duration.

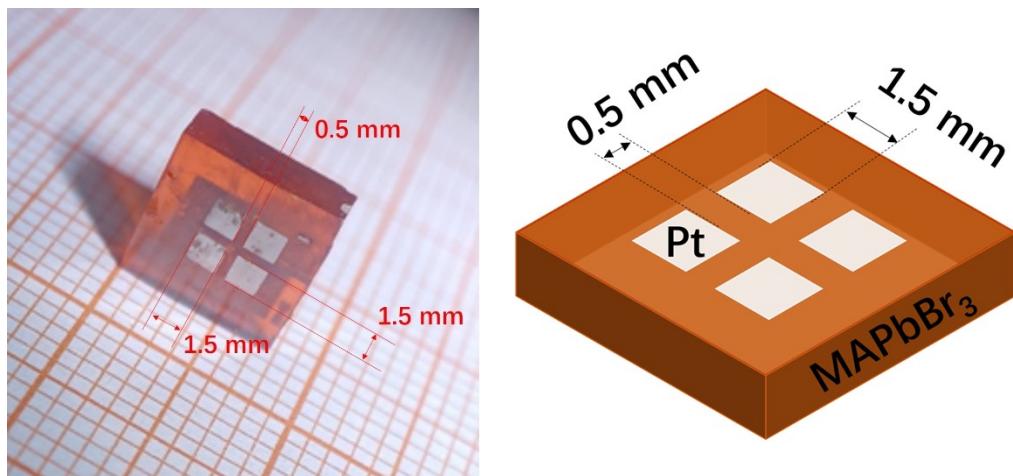


Fig. S1. Photograph of the VEC-MAPbBr₃ single crystal device structure.

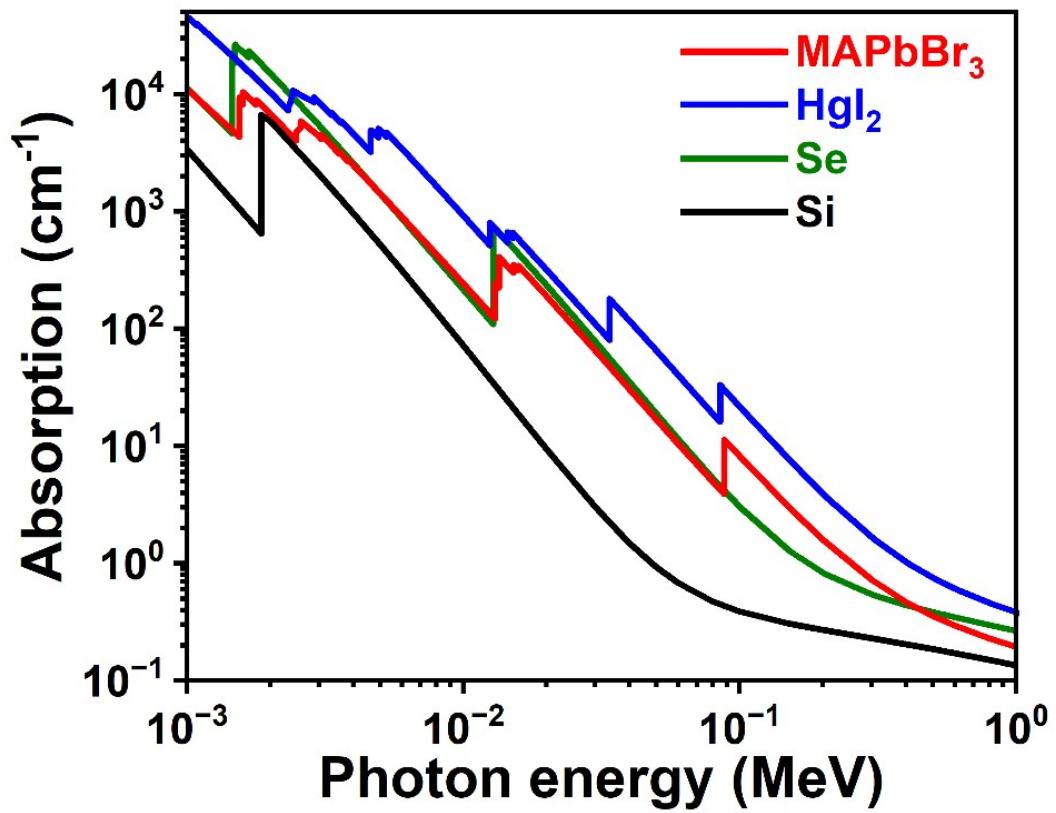


Fig. S2. Linear absorption coefficients of MAPbBr₃, HgI₂, Se, and Si as a function of photo energy from 0.001 to 1 MeV.

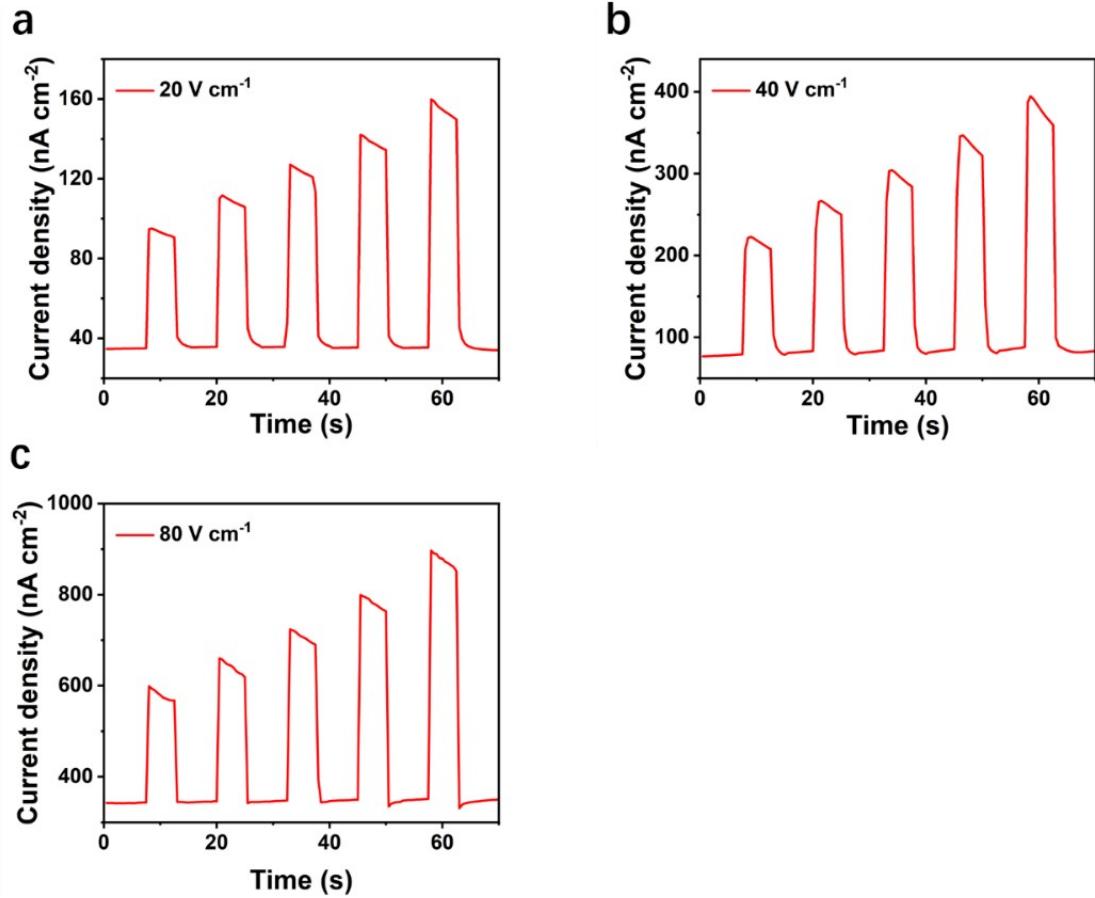


Fig. S3. Photocurrent-dose rate curves of the LPAC-MAPbBr₃ detector at electric field strengths of 20, 40, and 80 V cm^{-1} .

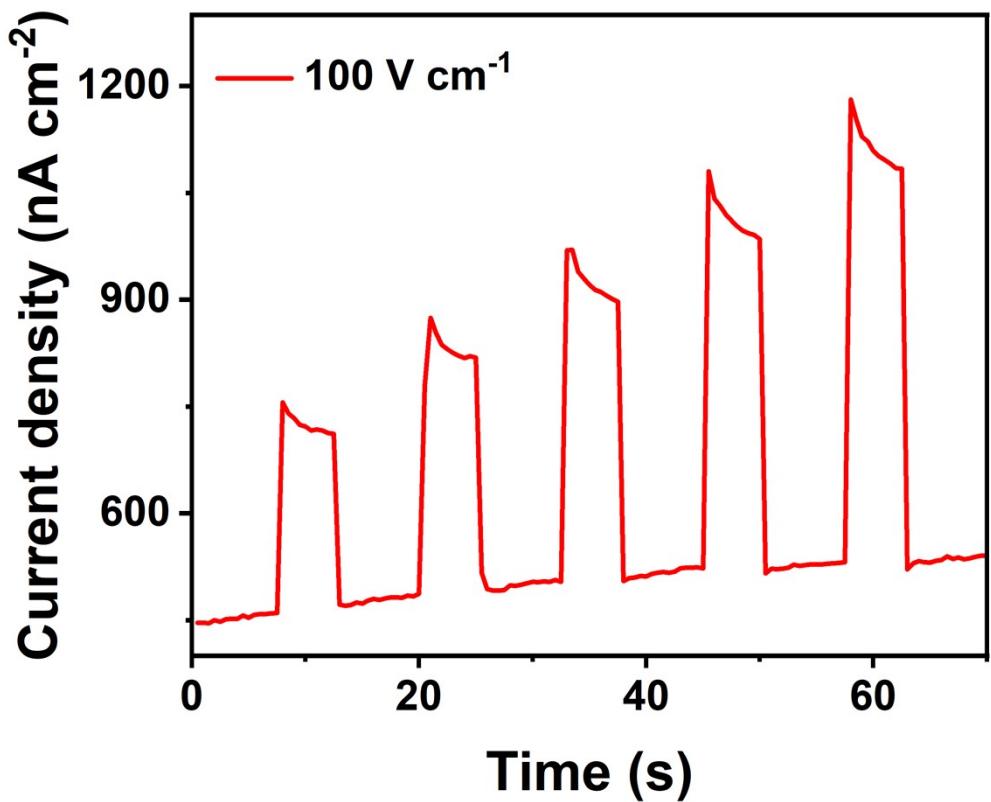


Fig. S4. Photocurrent-dose rate curves of the detector at an electric field strength of 100 V cm^{-1} .

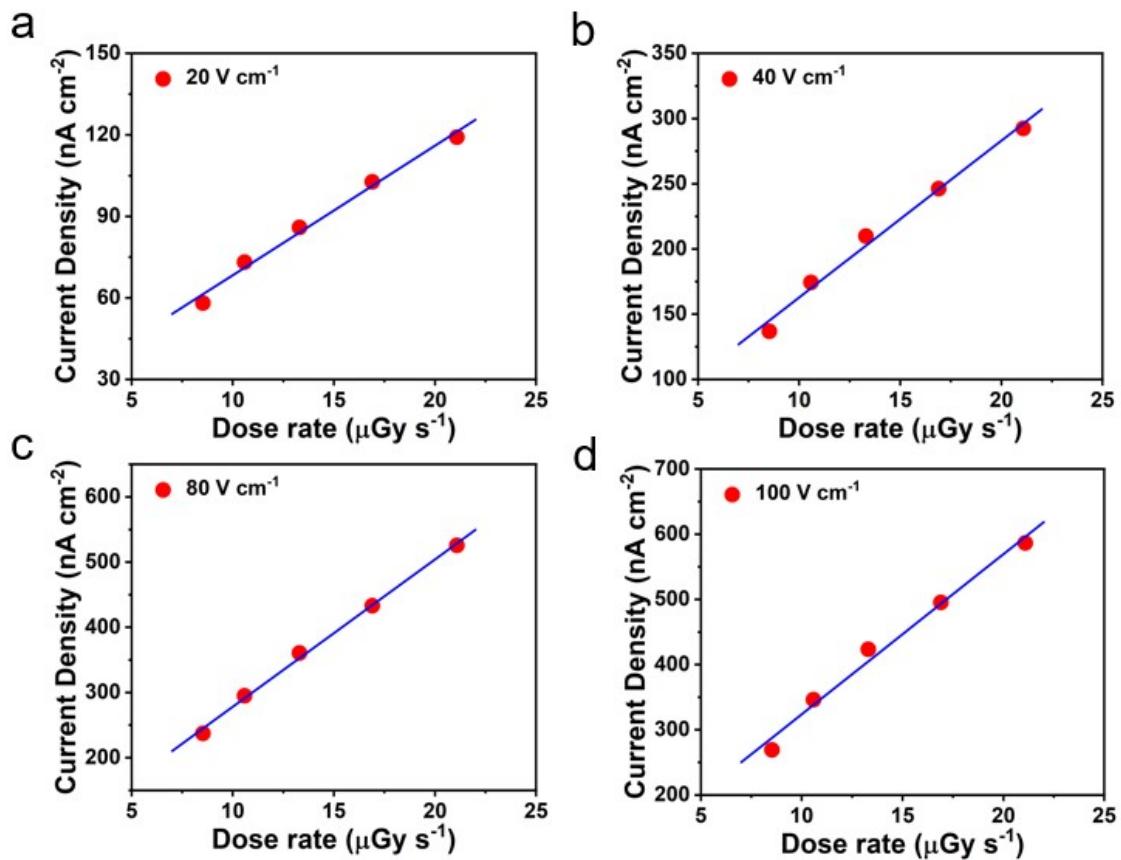


Fig. S5. Photocurrent response of the detector at different electric field strengths and various dose rates

under 100 kV_p X-ray illumination.

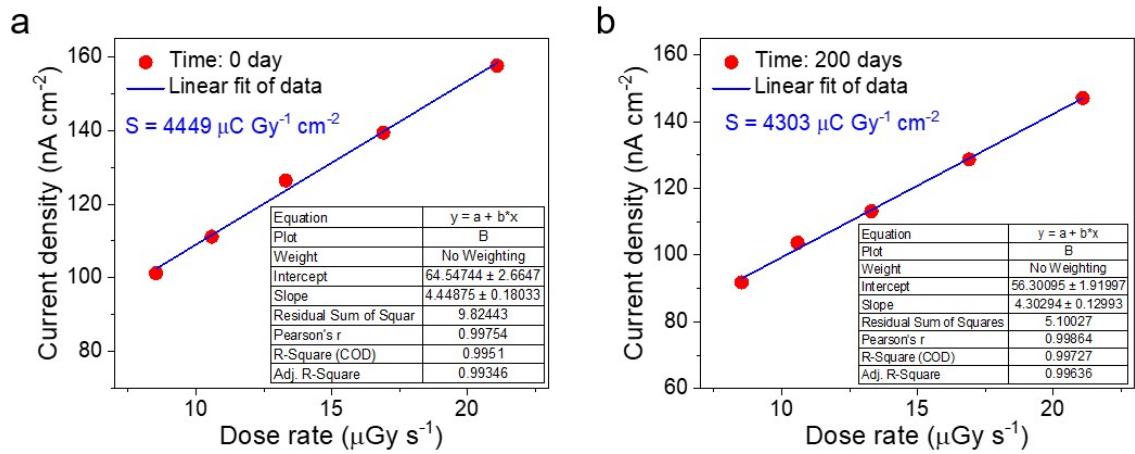


Fig. S6. Photocurrent response of the detector was assessed under 100 kV_p X-ray illumination at various dose rates, and the sensitivities were evaluated on day 0 and day 200.

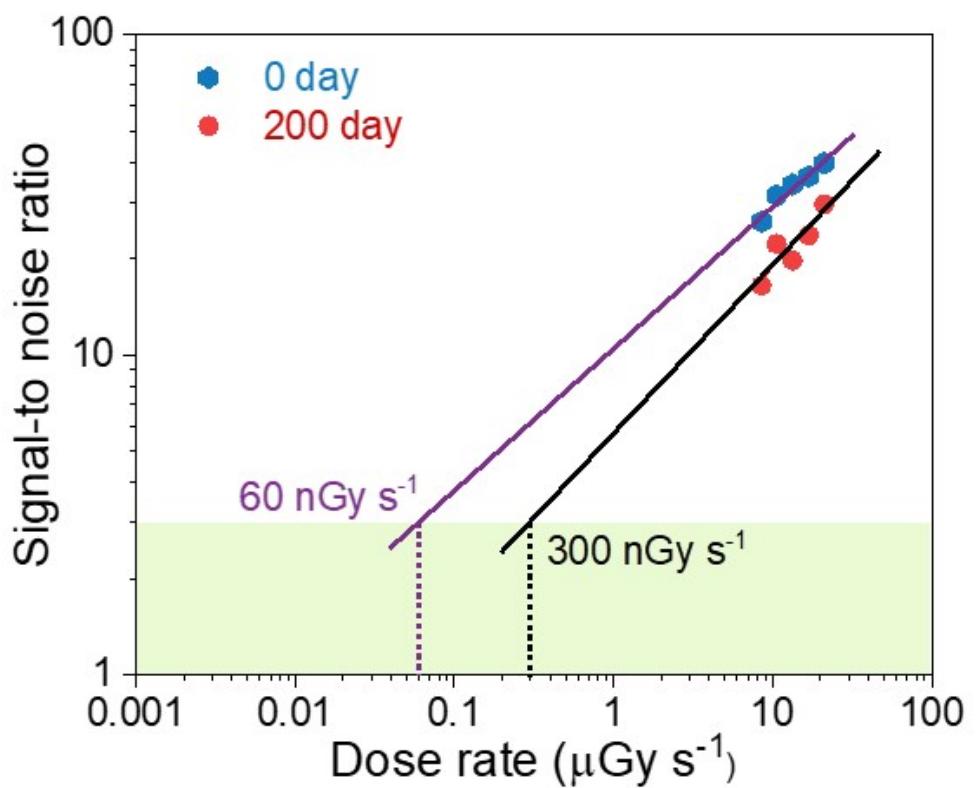


Fig. S7. Signal-to-noise ratio of the VEC-MAPbBr₃ SC detector on day 0 and day 200.

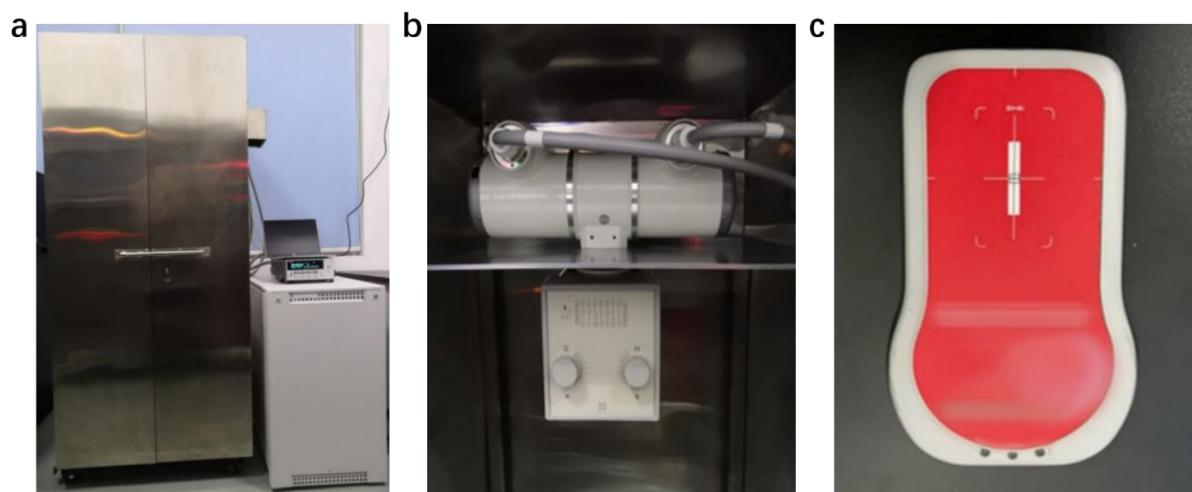


Fig. S8. Photographs of (a) the X-ray-generating and shielding device, (b) the X-ray tube and beam limiter, and (c) the Piranha 655 X-ray machine multifunctional quality detector.

Table S1. Summary of detailed fitting parameters of time-resolved photoluminescence (TRPL) spectroscopy for VEC-MAPbBr₃ and HT- MAPbBr₃.

Sample	VEC-MAPbBr ₃	HT- MAPbBr ₃
Model	ExpDec2	
Equation	$y = A_1 e^{-\frac{x}{\tau_1}} + A_2 e^{-\frac{x}{\tau_2}} + y_0$	
y_0	8.5657 ± 1.77196	4.94962 ± 0.85886
A_1	2006.22578 ± 13.05686	1947.27637 ± 17.06467
τ_1	154.4088 ± 1.86672	143.61114 ± 1.75293
A_2	330.27302 ± 11.48534	377.08082 ± 17.51037
τ_2	1149.76857 ± 49.00642	683.35276 ± 24.72292

Table S2. The detailed fitting results of the I - V curve for VEC-MAPbBr₃ single crystal.

VEC-MAPbBr ₃ single crystal			
Regimes	n = 1	n > 3	n = 2
Equation	$y = a + b*x$	$y = a + b*x$	$y = a + b*x$
Intercept	-8.75046 ± 0.01478	-11.3941 ± 0.09745	-8.2387 ± 0.01255
Slope	0.62977 ± 0.03057	3.76295 ± 0.07651	1.56053 ± 0.00687
Residual Sum of Squares	8.54E-04	0.06082	0.00264
Pearson's r	0.99649	0.99589	0.99941
R-Square (COD)	0.99298	0.9918	0.99882
Adj. R-Square	0.99064	0.99139	0.9988

Table S3. The detailed fitting results of the I - V curve for HT-MAPbBr₃ single crystal.

HT-MAPbBr ₃ single crystal			
Regimes	n = 1	n > 3	n = 2
Equation	$y = a + b*x$	$y = a + b*x$	$y = a + b*x$
Intercept	-8.00305 ± 0.00875	-9.47216 ± 0.0285	-8.38832 ± 0.03839
Slope	0.92236 ± 0.0111	2.13839 ± 0.01935	1.51949 ± 0.02021
Residual Sum of Squares	0.00146	0.00401	0.00278
Pearson's r	0.99928	0.99894	0.99657
R-Square (COD)	0.99855	0.99788	0.99315
Adj. R-Square	0.99841	0.99779	0.99297

Table S4. Summary of MAPbBr₃ SC properties and photodetector performances of resulting X-ray detectors in published representative work.

Ref.	Methods	FWHM of rocking curve (°)	E _g (eV)	PL peak (nm)	τ (ns)	n _{trap} (×10 ⁹ cm ⁻³)	Mobility μ (cm ² V ⁻¹ s ⁻¹)	Lowest detectable dose rate (μGy·S ⁻¹)	Sensitivity (μC Gy ⁻¹ cm ⁻²)
[1]	LDSC.1	0.0096 (200)	2.15	577	997	4.4		1.2	184.6
[2]	LDSC.2	0.0096 (100)	2.18	577	1099	4.5	88.6		2181
[3]	LTGC.1	0.013 (200)	2.24	545	962	5.2	81		
[4]	LTGC.2	0.019 (100)	2.24	547	897	6.7	83.9		
[5]	PA-ITC.1	0.008 (200)		533	44.87			0.087	15280
[6]	PA-ITC.2	0.127 (100)	2.23	546	923	6.6	39		
[7]	SL-ITC		2.16		17.14	16.9	60		632
[8]	RT-ITC	0.0253	2.29			6.59	18		
	ZT-ITC	0.0179				3.06	6		
	LT-ITC	0.0171				2.55	115		
[9]	AVC.1		2.21	570	978	5.8	115		
[10]	AVC.2			550			217	0.5	80
[11]	AVC.3		2.21				59.7		
[12]	AVC.4			542	242.8	7.96	35		
[13]	VTC		2.19			5.64	27.5	0.35	307
[14]	CGC	0.018 (110)	2.25						
[15]	STCAD	0.0112 (110)	2.3		411.47				426.43
[16]	LCMC	0.0123 (200)	2.17	578	1126	2.1	87.8	0.48	2975.7
[17]	ITC.1		2.18	574	300	30	24		
[18]	ITC.2			550	981	60	2.7		
[19]	ITC.3		2.24	537		26	4.36		
[20]	ITC.4				692		201	0.1	21000
[21]	PTG	0.00806 (100)	2.2	562	1002	4.25		0.67	7275
	VEC	0.00922 (001)	2.20	579	1150	2.28	130	0.054	24552

Table S5. Dose rate calibration for 100 kVp X-ray illumination.

Tube current (mA)	Dose rate 1 (μ Gy s ⁻¹)	Dose rate 2 (μ Gy s ⁻¹)	Dose rate 3 (μ Gy s ⁻¹)	Average dose rate (μ Gy s ⁻¹)
10	8.504	8.541	8.532	8.525666667
12.5	10.5	10.67	10.58	10.58333333
16	13.28	13.45	13.18	13.30333333
20	16.79	17.1	16.8	16.89666667
25	20.9	21.54	20.82	21.08666667

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